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## NTE74HC374 Integrated Circuit TTL – High Speed CMOS, Octal D–Type Flip–Flop with 3–State Outputs Common Output Control and Common Clock

**Description:**

The NTE74HC374 is a high speed octal D–type flip–flop with 3–state outputs in a 20–Lead DIP type package with the capability to drive 15 LS–TTL loads. The eight edge–triggered flip–flops enter data into their registers on the LOW to HIGH transition of clock (CP). The output enable ( $\overline{OE}$ ) controls the 3–state outputs and is independent of the register operation. When  $\overline{OE}$  is HIGH, the outputs are in the high–impedance state.

**Features:**

- Wide Power Supply Range: 2V to 6V
- High Noise Immunity:  $N_{IL} = 30\%$ ,  $N_{IH} = 30\%$  of  $V_{CC}$  at  $V_{CC} = 5V$
- Buffered Inputs
- Common Three–State Output Enable Control
- Three–State Outputs
- Bus Line Driving Capability
- Typical Propagation Delay (Clock to Q): 15ns at  $V_{CC} = 5V$ ,  $C_L = 15pF$ ,  $T_A = +25^\circ C$
- Fanout (Over Temperature Range):
  - Standard Outputs . . . 10 LS–TTL Loads
  - Bus Driver Outputs . . 15 LS–TTL Loads

**Absolute Maximum Ratings:** (Note 1, Note 2)

Supply Voltage, $V_{CC}$ .....	–0.5 to +7.0V
Clamp Diode Current, $I_{IK}, I_{OK}$ .....	±20mA
DC Drain Current (Per Output), $I_{OUT}$ .....	±35mA
DC Output Source or Sink Current (Per Output), $I_{OUT}$ .....	±25mA
DC $V_{CC}$ or GND Current (Per Pin), $I_{CC}$ .....	±50mA
Maximum Junction, $T_J$ .....	+150°C
Storage Temperature Range, $T_{stg}$ .....	–65°C to +150°C
Typical Thermal Resistance, Junction–to–Ambient, $R_{thJA}$ .....	69°C/W
Lead Temperature (During Soldering, 10sec), $T_L$ .....	+300°C

Note 1. Absolute Maximum Ratings are those values beyond which damage to the device may occur.  
 Note 2. Unless otherwise specified, all voltages are referenced to GND.

### Recommended Operating Conditions:

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	$V_{CC}$	2.0	–	6.0	V
DC Input or Output Voltage	$V_{IN}, V_{OUT}$	0	–	$V_{CC}$	V
Operating Temperature Range	$T_A$	–40	–	+85	°C
Input Rise or Fall Times $V_{CC} = 2.0V$	$t_r, t_f$	–	–	1000	ns
$V_{CC} = 4.5V$		–	–	500	ns
$V_{CC} = 6.0V$		–	–	400	ns

### DC Electrical Characteristics:

Parameter	Symbol	Test Conditions	$V_{CC}$	$T_A = +25^\circ C$		$T_A = -40^\circ \text{ to } +85^\circ C$		Unit
				Typ	Guaranteed Limits			
Minimum HIGH Level Input Voltage	$V_{IH}$		2.0	–	1.5	1.5	V	
			4.5	–	3.15	3.15	V	
			6.0	–	4.2	4.2	V	
Maximum LOW Level Input Voltage	$V_{IL}$		2.0	–	0.5	0.5	V	
			4.5	–	1.35	1.35	V	
			6.0	–	1.8	1.8	V	
Minimum HIGH Level Output Voltage	$V_{OH}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OUT} = -20\mu A$	–	$V_{CC}$	$V_{CC}^{-0.1}$	$V_{CC}^{-0.1}$	V
			$I_{OUT} = -6mA$	4.5	–	3.98	3.84	V
			$I_{OUT} = -7.8mA$	6.0	–	5.48	5.34	V
Minimum LOW Level Output Voltage	$V_{OL}$	$V_{IN} = V_{IH}$ or $V_{IL}$	$I_{OUT} = 20\mu A$	–	–	0.1	0.1	V
			$I_{OUT} = 6mA$	4.5	0.2	0.26	0.33	V
			$I_{OUT} = 7.8mA$	6.0	0.2	0.26	0.33	V
Maximum Input Leakage Current	$I_{IN}$	$V_{IN} = V_{CC}$ or GND	6.0	–	$\pm 0.1$	$\pm 1.0$	$\mu A$	
Maximum Quiescent Supply Current	$I_{CC}$	$V_{IN} = V_{CC}$ or GND, $I_{OUT} = 0\mu A$	6.0	–	8.0	80	$\mu A$	
Three-State Leakage Current	$I_{OZ}$	$V_{IN} = V_{IH}$ or $V_{IL}$	6.0	–	$\pm 0.5$	$\pm 5.0$	$\mu A$	

### Prerequisite for Switching Specifications:

Parameter	Symbol	Test Conditions	$V_{CC}$	$T_A = +25^\circ C$		$T_A = -40^\circ \text{ to } +85^\circ C$		Unit
				Typ	Guaranteed Limits			
Maximum Clock Frequency	$f_{MAX}$		2.0	–	6	5	MHz	
			4.5	–	30	25	MHz	
			6.0	–	35	29	MHz	
Clock Pulse Width	$t_W$		2.0	–	80	100	ns	
			4.5	–	16	20	ns	
			6.0	–	14	17	ns	
Setup Time (Data to Clock)	$t_{SU}$		2.0	–	60	75	ns	
			4.5	–	12	15	ns	
			6.0	–	10	13	ns	
Hold Time (Data to Clock)	$t_H$		2.0	–	5	5	ns	
			4.5	–	5	5	ns	
			6.0	–	5	5	ns	

**Switching Specifications:** ( $t_r = t_f = 6\text{ns}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	V <sub>CC</sub>	T <sub>A</sub> = +25°C		T <sub>A</sub> = -40° to +85°C		Unit
				Typ	Guaranteed Limits			
Propagation Delay Time (Clock to Output)	t <sub>PLH</sub> , t <sub>PHL</sub>	C <sub>L</sub> = 50pF	2.0	-	165	205	ns	
			4.5	-	33	41	ns	
		C <sub>L</sub> = 15pF	5.0	15	-	-	ns	
		C <sub>L</sub> = 50pF	6.0	-	28	35	ns	
Propagation Delay Time (Disable to Q)	t <sub>PLZ</sub> , t <sub>PHZ</sub>	C <sub>L</sub> = 50pF	2.0	-	135	170	ns	
			4.5	-	27	34	ns	
		C <sub>L</sub> = 15pF	5.0	11	-	-	ns	
		C <sub>L</sub> = 50pF	6.0	-	23	29	ns	
Propagation Delay Time (Output Enable to Q)	t <sub>PZL</sub> , t <sub>PZH</sub>	C <sub>L</sub> = 50pF	2.0	-	150	190	ns	
			4.5	-	30	38	ns	
		C <sub>L</sub> = 15pF	5.0	12	-	-	ns	
		C <sub>L</sub> = 50pF	6.0	-	26	33	ns	
Maximum Clock Frequency	f <sub>MAX</sub>	C <sub>L</sub> = 15pF	5.0	60	-	-	MHz	
Output Transition Time	t <sub>TLH</sub> , t <sub>THL</sub>	C <sub>L</sub> = 50pF	2.0	-	60	75	ns	
			4.5	-	12	15	ns	
			6.0	-	10	13	ns	
Maximum Input Capacitance	C <sub>IN</sub>		-	-	10	10	pF	
Minimum Three-State Output Capacitance	C <sub>O</sub>		-	-	20	20	pF	
Power Dissipation Capacitance	C <sub>PD</sub>	C <sub>L</sub> = 15pF, Note 3	5.0	39	-	-	pF	

Note 3. C<sub>PD</sub> is used to determine the dynamic power consumption, per channel.  
 $P_D = C_{PD} V_{CC}^2 f_i + \sum V_{CC}^2 f_o C_L$  where  $f_i$  = Input Frequency,  $f_o$  = Output Frequency,  
 $C_L$  = Output Load Capacitance,  $V_{CC}$  = Supply Voltage.

**Truth Table:**

Inputs			Output
$\overline{OE}$	CP	Data D <sub>n</sub>	Q <sub>n</sub>
L	↑	H	H
L	↑	L	L
L	L	X	Q0
H	X	X	Z

H = HIGH Level (Steady State)

L = LOW Level (Steady State)

X = Don't Care

↑ = Transition from LOW to HIGH Level

Q0 = The level of Q before the indicated steady state input conditions were established.

Z = High Impedance State

### Pin Connection Diagram

